

CONTENTS

1 Elementary Crystallography	1
2 The Production and Properties of X-rays	58
3 Fundamental Principles of X-ray Diffraction	120
4 Photographic Powder Techniques	175
5 Diffractometric Powder Technique	271
6 The Interpretation of Powder Diffraction Data	419
7 Qualitative and Quantitative Analysis of Crystalline Powders	505
8 The Precision Determination of Lattice Constants	566
9 Crystallite Size and Lattice Strains From Line Broadening	618
10 Investigation of Preferred Orientation and Texture	709
11 Stress Measurement in Metals	755
12 Radial-Distribution Studies of Noncrystalline Materials	791
Appendix I Layout for a Diffraction Laboratory	861
Appendix II The Handling and Processing of X-ray Film	867
Appendix III Miscellaneous Constants and Numerical Data	872
Appendix IV International Atomic Weights	873
Appendix V Mass Absorption Coefficients μ/p of the Elements ($Z = 1$ to 83) for a Selection of Wavelengths	875
Appendix VI Quadratic Forms for the Cubic System	878
Appendix VII Atomic and Ionic Scattering Factors	880
Appendix VIII Lorentz and Polarization Factors	892
Appendix IX Temperature Factor Table	896
Appendix X Warren's Powder Pattern Power Theorem	897
Author Index	901
Subject Index	923